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RJK6025DPH-E0-VB Datasheet

N-Channel 650V (D-S) Power MOSFET

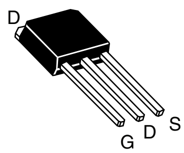
PRODUCT SUMMARY		
V_{DS} (V)	650	
$R_{DS(on)}$ (Ω)	V_{GS} = 10 V	4
Q_g (Max.) (nC)	11	
Q_{gs} (nC)	2.3	
Q_{gd} (nC)	5.2	
Configuration	Single	

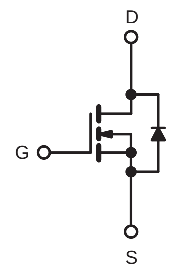
FEATURES

- Low Gate Charge Q_g Results in Simple Drive Requirement
- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche Voltage and Current
- Compliant to RoHS directive 2002/95/EC

Available
RoHS
COMPLIANT

IPAK
(TO-251)





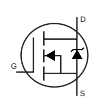
N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS T_C = 25 °C, unless otherwise noted					
PARAMETER			**SYMBOL**	**LIMIT**	**UNIT**
Drain-Source Voltage			V_{DS}	650	V
Gate-Source Voltage			V_{GS}	± 30	
Continuous Drain Current[e]	V_{GS} at 10 V	T_C = 25 °C	I_D	2 .0	A
Continuous Drain Current		T_C = 100 °C		1.28	
Pulsed Drain Current[a]			I_{DM}	8	
Linear Derating Factor				0.48	W/°C
Single Pulse Avalanche Energy[b]			E_{AS}	165	mJ
Repetitive Avalanche Current[a]			I_{AR}	2	A
Repetitive Avalanche Energy[a]			E_{AR}	6	mJ
Maximum Power Dissipation	T_C = 25 °C		P_D	45	W
Peak Diode Recovery dV/dt[c]			dV/dt	2.8	V/ns
Operating Junction and Storage Temperature Range			T_J, T_{stg}	- 55 to + 150	°C
Soldering Recommendations (Peak Temperature)[d]	for 10 s			300	
Mounting Torque	6-32 or M3 screw			10	lbf · in
				1.1	N · m

Notes
a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Starting T_J = 25 °C, L = 24 mH, R_G = 25 Ω, I_{AS} = 3.2 A (see fig. 12).
c. $I_{SD} \leq 3.2$ A, dI/dt ≤ 90 A/μs, $V_{DD} \leq V_{DS}$, $T_J \leq 150$ °C.
d. 1.6 mm from case.
e. Drain current limited by maximum junction temperature.

THERMAL RESISTANCE RATINGS				
PARAMETER	**SYMBOL**	**TYP.**	**MAX.**	**UNIT**
Maximum Junction-to-Ambient	R_{thJA}	-	65	°C/W
Maximum Junction-to-Case (Drain)	R_{thJC}	-	2.1	°C/W

SPECIFICATIONS T_J = 25 °C, unless otherwise noted

PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static						
Drain-Source Breakdown Voltage	V_{DS}	V_{GS} = 0 V, I_D = 250 μA	650	-	-	V
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to 25 °C, I_D = 1 mA[d]	-	670	-	mV/°C
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$, I_D = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I_{GSS}	V_{GS} = ± 30 V	-	-	± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	V_{DS} = 650 V, V_{GS} = 0 V	-	-	25	μA
		V_{DS} = 520 V, V_{GS} = 0 V, T_J = 125 °C	-	-	250	
Drain-Source On-State Resistance	$R_{DS(on)}$	V_{GS} = 10 V, I_D = 1 A [b]	-	4.0	-	Ω
Forward Transconductance	g_{fs}	V_{DS} = 50 V, I_D = 1 A	3.9	-	-	S
Dynamic						
Input Capacitance	C_{iss}	V_{GS} = 0 V, V_{DS} = 25 V, f = 1.0 MHz, see fig. 5	-	417	-	pF
Output Capacitance	C_{oss}		-	45	-	
Reverse Transfer Capacitance	C_{rss}		-	5	-	
Output Capacitance	C_{oss}	V_{GS} = 0 V, V_{DS} = 1.0 V, f = 1.0 MHz	-	912	-	
		V_{GS} = 0 V, V_{DS} = 520 V, f = 1.0 MHz	-	26		
Effective Output Capacitance	C_{oss} eff.	V_{GS} = 0 V, V_{DS} = 0 V to 520 V[c]	-	42	-	
Total Gate Charge	Q_g	V_{GS} = 10 V, I_D = 12 A, V_{DS} = 400 V see fig. 6 and 13[b]	-	-	11	nC
Gate-Source Charge	Q_{gs}		-	-	2.3	
Gate-Drain Charge	Q_{gd}		-	-	5.2	
Turn-On Delay Time	$t_{d(on)}$	V_{DD} = 325 V, I_D = 1.2A, R_G = 9.1 Ω, R_D = 62 Ω, see fig. 10[b]	-	14	-	ns
Rise Time	t_r		-	20	-	
Turn-Off Delay Time	$t_{d(off)}$		-	34	-	
Fall Time	t_f		-	18	-	
Drain-Source Body Diode Characteristics						
Continuous Source-Drain Diode Current	I_S	MOSFET symbol showing the integral reverse p - n junction diode 	-	-	2	A
Pulsed Diode Forward Current[a]	I_{SM}		-	-	8	
Body Diode Voltage	V_{SD}	T_J = 25 °C, I_S = 3.2 A, V_{GS} = 0 V[b]	-	-	1.5	V
Body Diode Reverse Recovery Time	t_{rr}	T_J = 25 °C, I_F = 3.2 A, dI/dt = 100 A/μs[b]	-	180	230	ns
Body Diode Reverse Recovery Charge	Q_{rr}		-	2.1	3.2	μC
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)				

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width ≤ 300 μs; duty cycle ≤ 2 %.
c. C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DS}.
d. t = 60 s, f = 60 Hz.

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

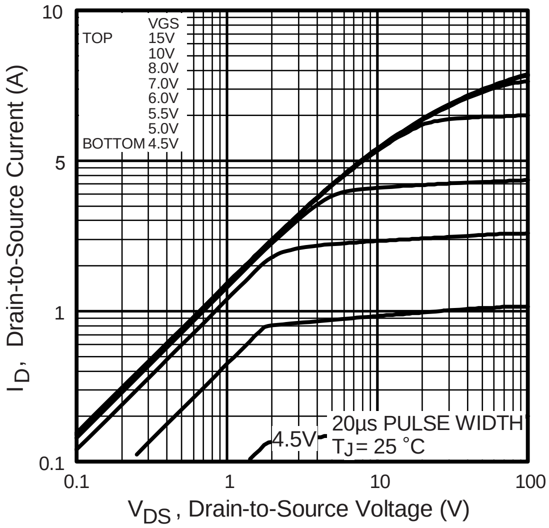


Fig. 1 - Typical Output Characteristics

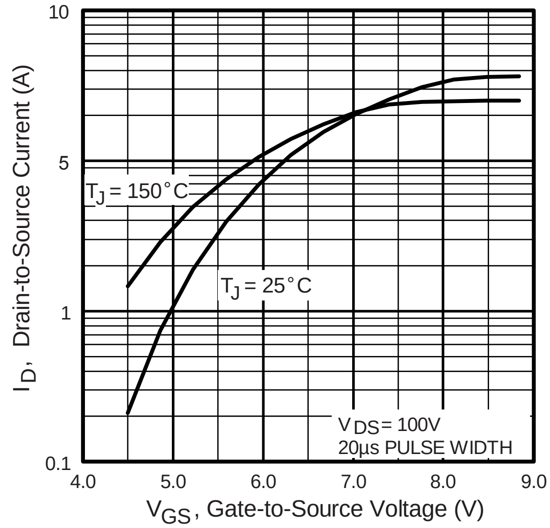


Fig. 3 - Typical Transfer Characteristics

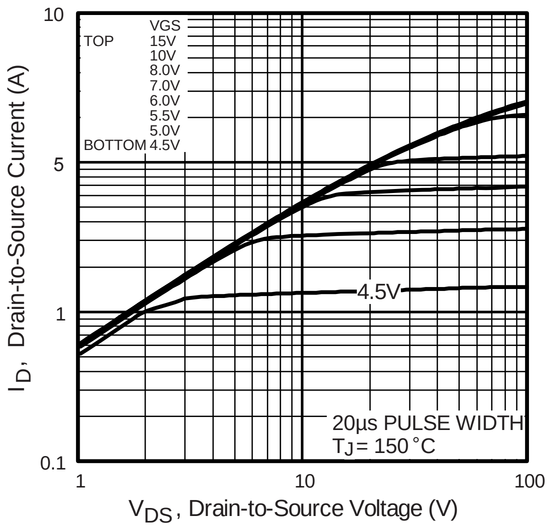


Fig. 2 - Typical Output Characteristics

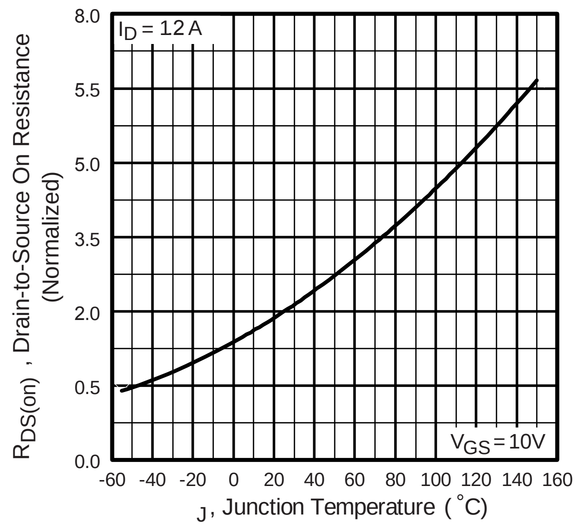


Fig. 4 - Normalized On-Resistance vs. Temperature

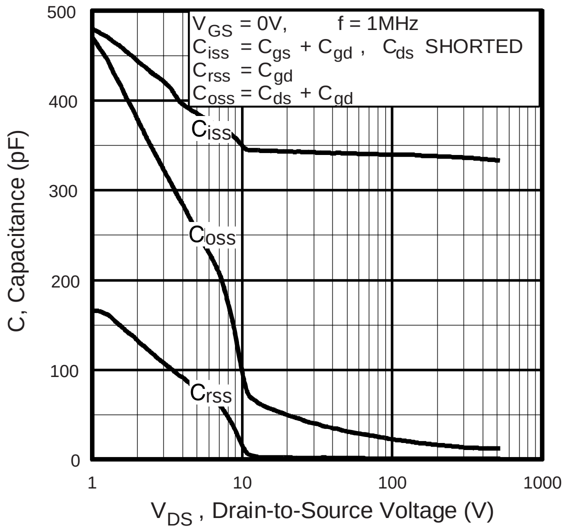


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

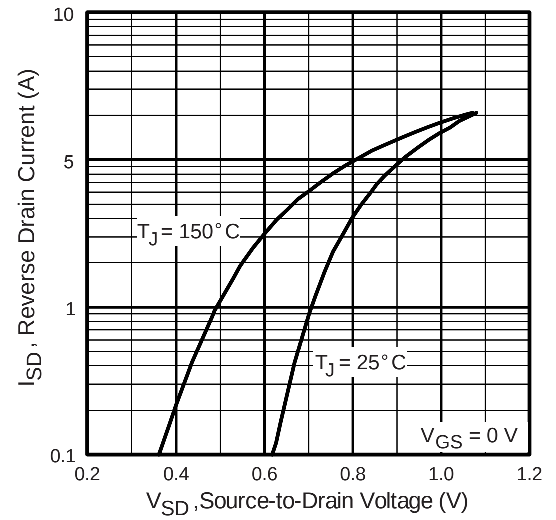


Fig. 7 - Typical Source-Drain Diode Forward Voltage

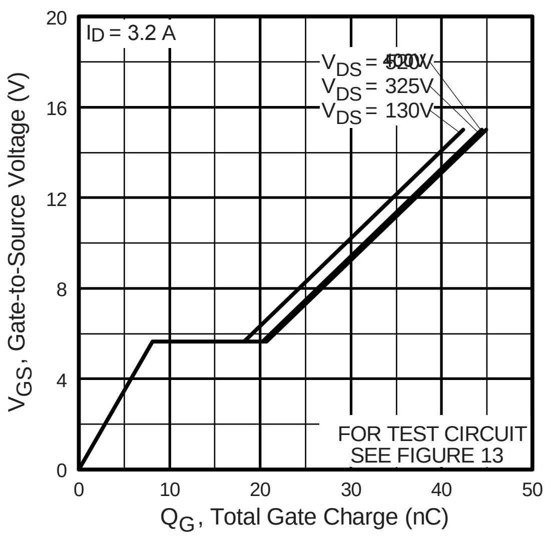


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

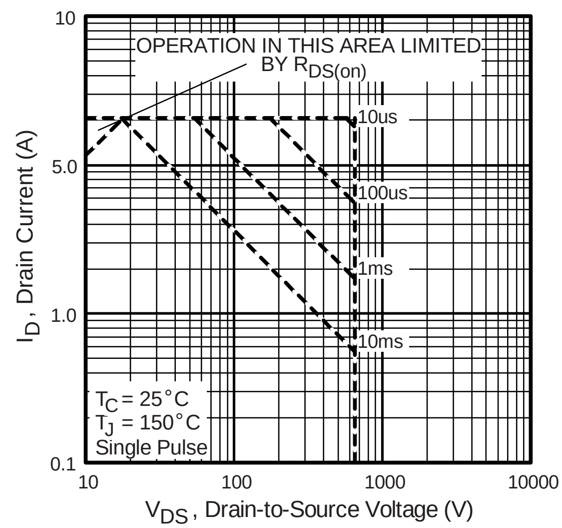


Fig. 8 - Maximum Safe Operating Area

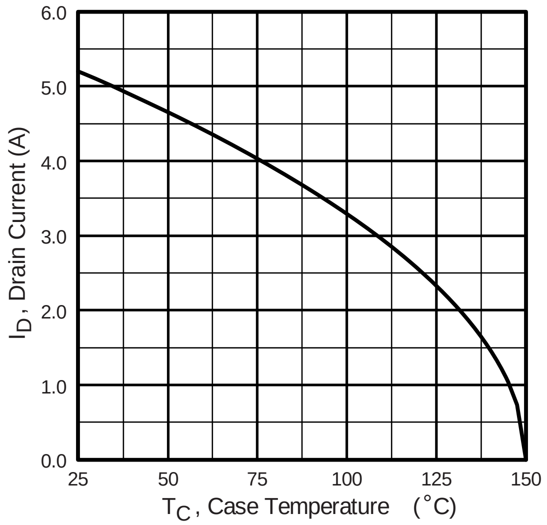


Fig. 9 - Maximum Drain Current vs. Case Temperature

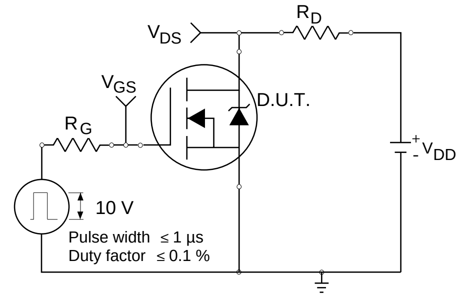


Fig. 10a - Switching Time Test Circuit

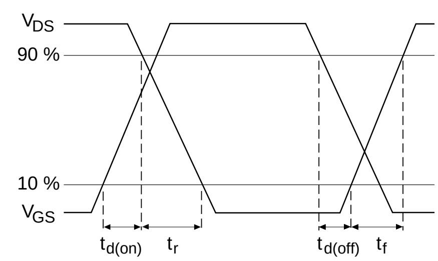


Fig. 10b - Switching Time Waveforms

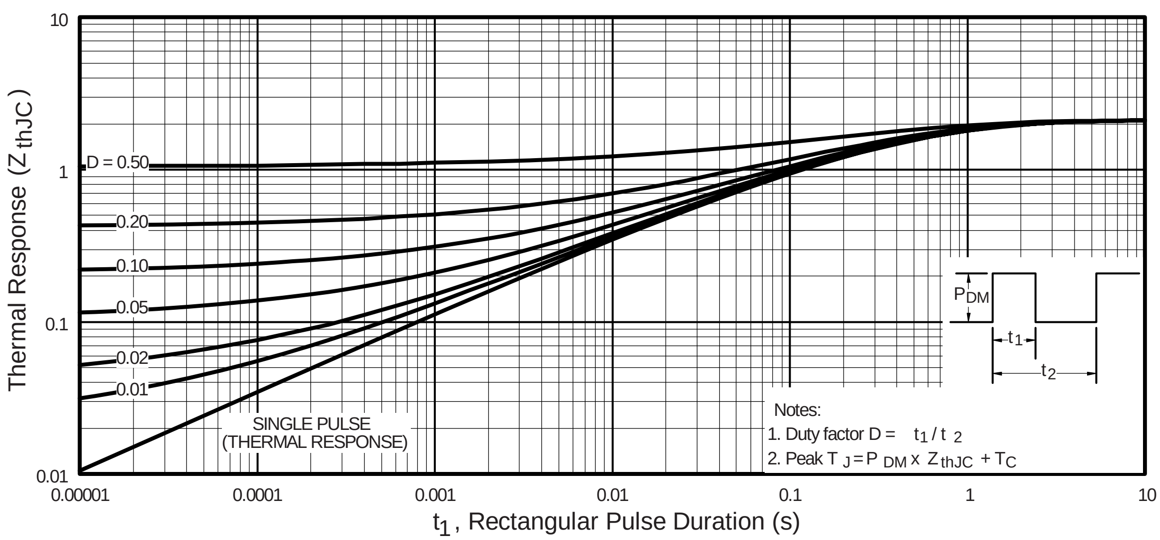


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

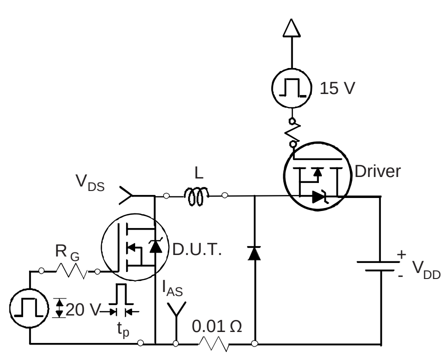


Fig. 12a - Unclamped Inductive Test Circuit

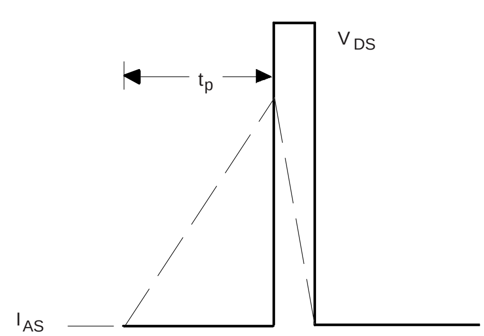


Fig. 12b - Unclamped Inductive Waveforms

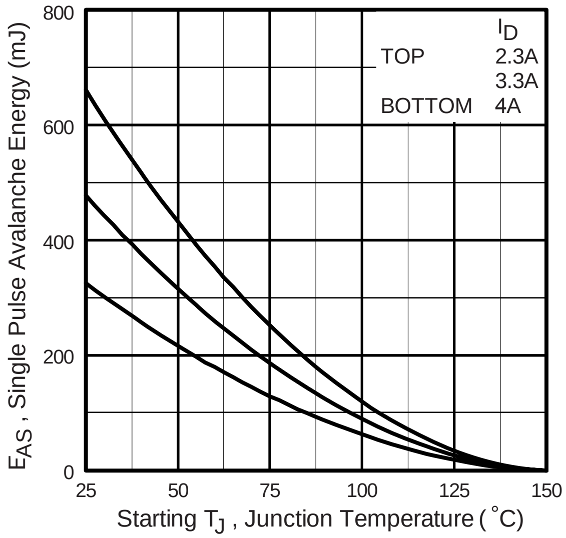


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

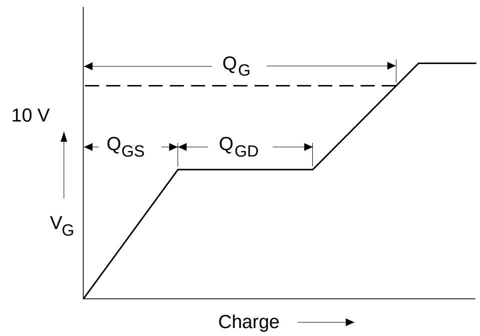


Fig. 13a - Basic Gate Charge Waveform

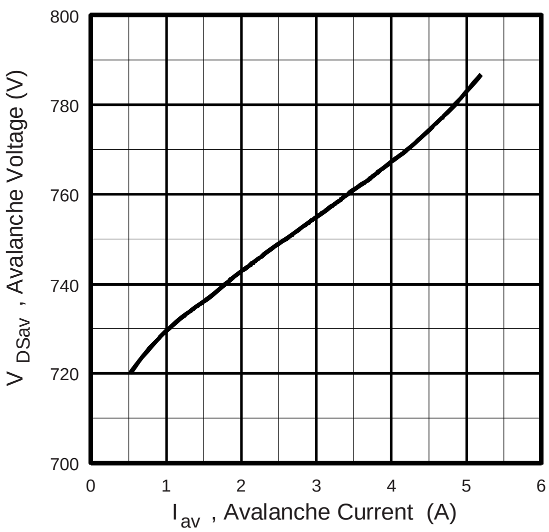


Fig. 12d - Typical Drain-to Source Voltage vs. Avalanche Current

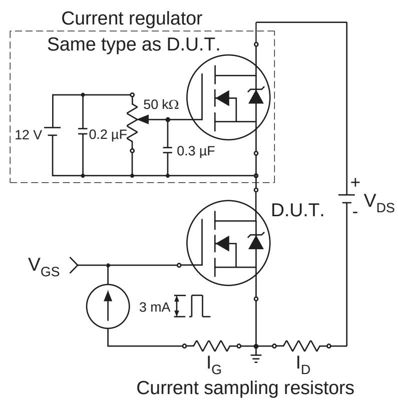
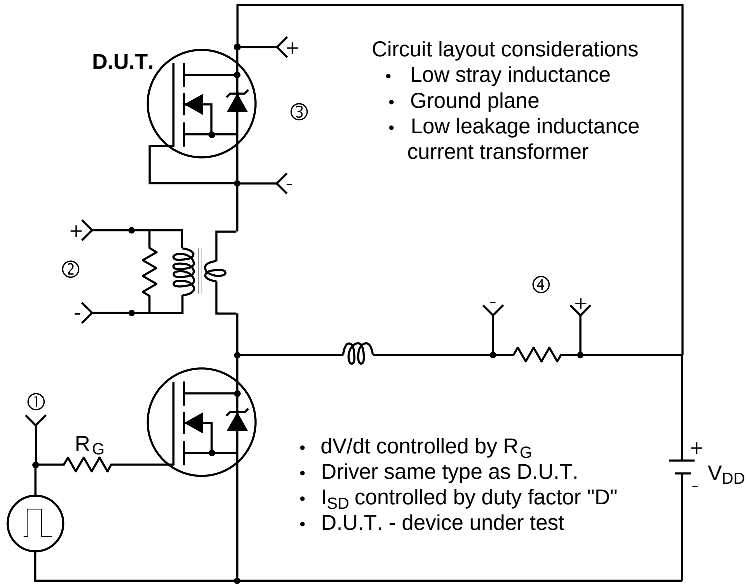
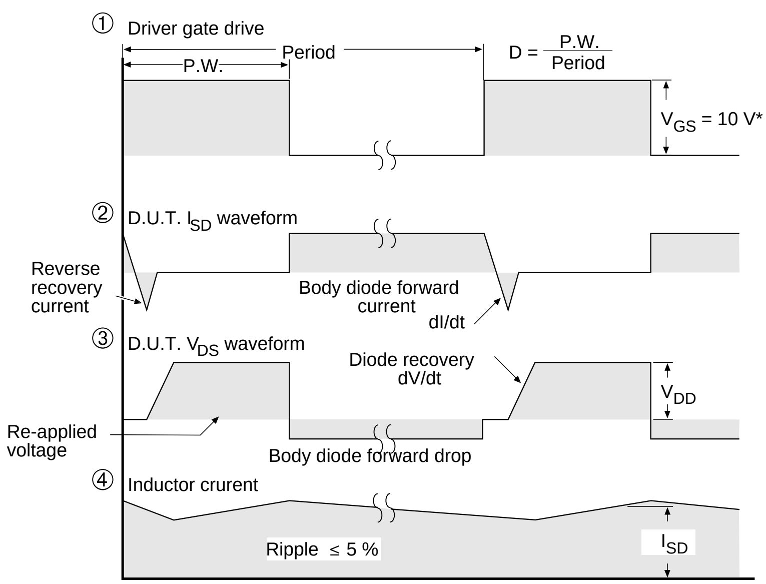


Fig. 13b - Gate Charge Test Circuit

Peak Diode Recovery dV/dt Test Circuit

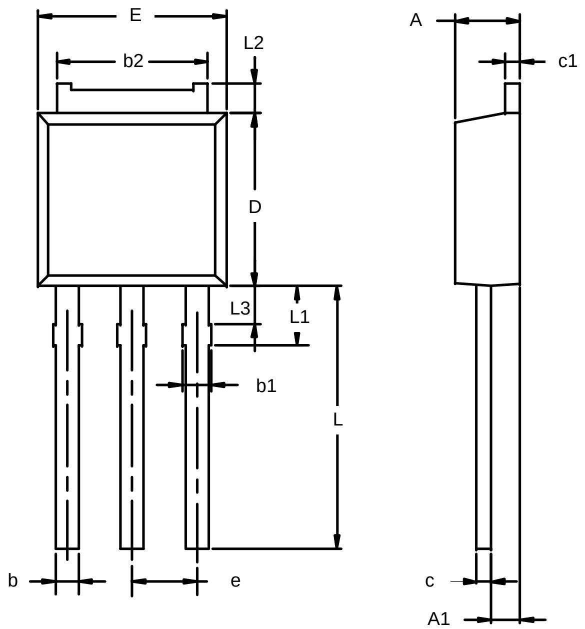




* V_{GS} = 5 V for logic level devices

Fig. 14 - For N-Channel

TO-251AA



Note: Dimension L3 is for reference only.

Dim	MILLIMETERS		INCHES	
	Min	Max	Min	Max
A	2.21	2.38	0.087	0.094
A1	0.89	1.14	0.035	0.045
b	0.71	0.89	0.028	0.035
b1	0.76	1.14	0.030	0.045
b2	5.23	5.43	0.206	0.214
c	0.46	0.58	0.018	0.023
c1	0.46	0.58	0.018	0.023
D	5.97	6.22	0.235	0.245
E	6.48	6.73	0.255	0.265
e	2.28 BSC		0.090 BSC	
L	3.89	9.53	0.153	0.375
L1	1.91	2.28	0.075	0.090
L2	0.89	1.27	0.035	0.050
L3	1.15	1.52	0.045	0.060

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